SX-R 20-1 set

Near-Field Probe 1 GHz up to 20 GHz



Short description

The SX-R 20-1 set consists of a passive near-field probe for the measurement of high-frequency magnetic fields up to 20 GHz during development. The probe head of the SX-R 20-1 allows measurements close to the electronic assembly, e.g. on individual IC pins, conductors, components and their connections to locate sources of interference. The field orientation and field distribution on the electronic assembly can be determined by guiding the near-field probe accordingly. The near-field probe is small and handy. It has a sheath current attenuation and is electrically shielded.
The near-field probe is connected to a spectrum analyzer or an oscilloscope with 50 Ω input.

Scope of delivery

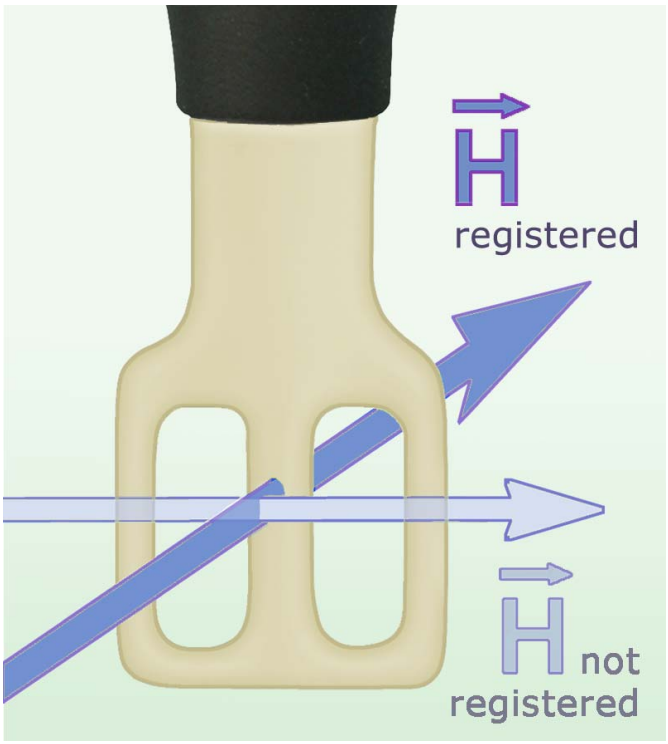
1x SX-R 20-1, H-Field Probe 1 GHz up to 20 GHz
1x SMA-SMA 1 m es, SMA-SMA Shielded Measurement Cable
1x Case 4, System Case Near-Field Probes for 4 probes

Technical parameters

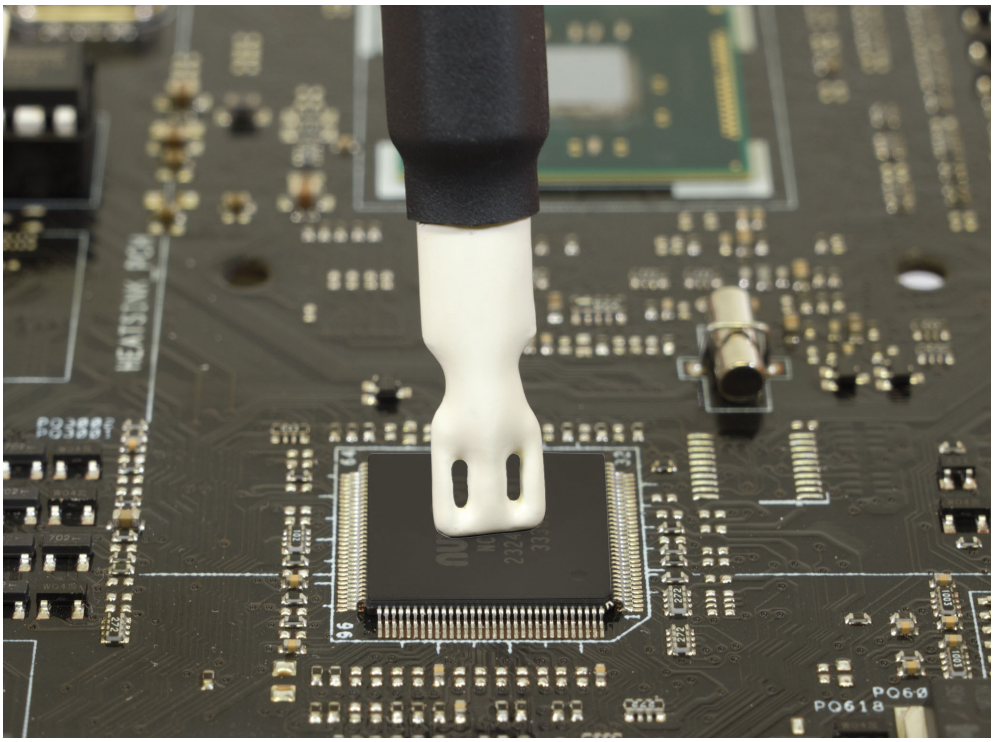
Frequency range	1 GHz ... 20 GHz
Probe head dimensions	≈ 6x6 mm
Connector - output	SMA, female, jack

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ABSOLUTE EMC
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Measuring principle



Application SX-R 20-1



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